2SB0767 (2SB767)

Silicon PNP epitaxial planar type

For low-frequency output amplification Complementary to 2SD0875 (2SD875)

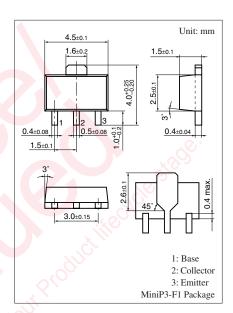
■ Features

- Large collector power dissipation P_C
- ullet High collector-emitter voltage (Base open) V_{CEO}
- Mini type package, allowing downsizing of the equipment and automatic insertion through the tape packing and the magazine packing

■ Absolute Maximum Ratings $T_a = 25$ °C

Parameter	Symbol	Rating	Unit	
Collector-base voltage (Emitter open)	V_{CBO}	-80	V	
Collector-emitter voltage (Base open)	V_{CEO}	-80	V	
Emitter-base voltage (Collector open)	V_{EBO}	-5	V	
Peak collector current	I_{CP}	-1	A	
Collector current	I_{C}	- 0.5	A	
Collector power dissipation *	P _C	1	W	
Junction temperature	T _j	150	°CO	
Storage temperature	T _{stg}	-55 to +150	°C	

Note) *: Print circuit board: Copper foil area of 1 cm² or more, and the board thickness of 1.7 mm for the collector portion.



Marking Symbol: C

■ Electrical Characteristics $T_a = 25$ °C ± 3 °C

Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Collector-base cutoff current (Emitter open)	I_{CBO}	$V_{CB} = -20 \text{ V}, I_E = 0$			- 0.1	μΑ
Collector-base voltage (Emitter open)	V_{CBO}	$I_C = -10 \mu A, I_E = 0$	-80			V
Collector-emitter voltage (Base open)	V _{CEO}	$I_C = -100 \mu\text{A}, I_B = 0$	-80			V
Emitter-base voltage (Collector open)	V _{EBO}	$I_E = -10 \ \mu A, I_C = 0$	-5			V
Forward current transfer ratio *1	h _{FE1} *2	$V_{CE} = -10 \text{ V}, I_{C} = -150 \text{ mA}$	90		220	
-allo	h _{FE2}	$V_{CE} = -5 \text{ V}, I_C = -500 \text{ mA}$	50	100		
Collector-emitter saturation voltage *1	V _{CE(sat)}	$I_C = -300 \text{ mA}, I_B = -30 \text{ mA}$		- 0.2	- 0.4	V
Base-emitter saturation voltage *1	V _{BE(sat)}	$I_C = -300 \text{ mA}, I_B = -30 \text{ mA}$		- 0.85	-1.20	V
Transition frequency	f_T	$V_{CB} = -10 \text{ V}, I_E = 50 \text{ mA}, f = 200 \text{ MHz}$		120		MHz
Collector output capacitance	C _{ob}	$V_{CB} = -10 \text{ V}, I_E = 0, f = 1 \text{ MHz}$		20	30	pF
(Common base, input open circuited)						

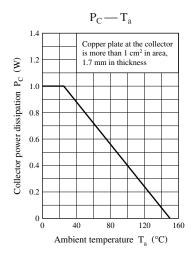
Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

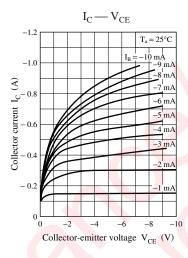
2. *1: Pulse measurement

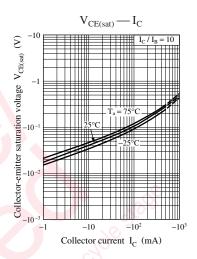
*2: Rank classification

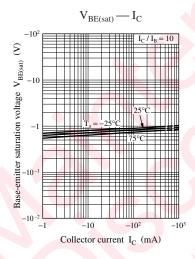
Rank	Q	R
h _{FE1}	90 to 155	130 to 220

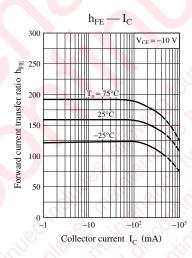
Note) The part numbers in the parenthesis show conventional part number.

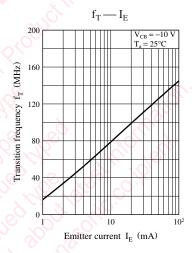


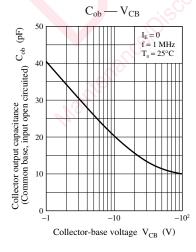


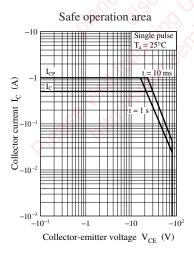












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